



SMC-02-1259

December 15, 2003

To: Commissioner for Patents
P.O.Box 1450
Alexandria, VA 22313-1450

Fr: George O. Saile, Reg. No. 19,572
28 Davis Avenue
Poughkeepsie, N.Y. 12603

Subject: | Serial No. 10/671,293 09/25/03 |

Chung-Hui Chen

SELF-LEAKAGE DETECTION CIRCUIT OF
DECOUPLING CAPACITOR IN MOS
TECHNOLOGY

INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO-1449, Information Disclosure Citation
In An Application.

The following Patents and/or Publications are submitted to
comply with the duty of disclosure under CFR 1.97-1.99 and
37 CFR 1.56.

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being
deposited with the United States Postal Service as first class
mail in an envelope addressed to: Commissioner for Patents,
P.O. Box 1450, Alexandria, VA 22313-1450, on December 19, 2003.

Stephen B. Ackerman, Reg.# 37761

Signature/Date

 12/19/03

The following two U.S. Patents teach a circuit to detect a defective decoupling capacitor during a power-up test:

- 1) U.S. Patent 5,506,457 to Krauter et al., "Electronic Switch for Decoupling Capacitor."
- 2) U.S. Patent 6,307,250 to Krauter et al., "Electronic Switch for Decoupling Capacitor."

U.S. Patent 5,789,964 to Voldman, "Decoupling Capacitor Network for Off-State Operation," discloses a method to detect a defective decoupling capacitor during power-up and to switch in a capacitor during an ESD event.

U.S. Patent Application Publication US 2002/0081832 A1 to Bernstein et al., "Intralevel Decoupling Capacitor, Method of Manufacture and Testing Circuit of the Same," describes a circuit to test decoupling capacitors in an integrated circuit device.

Sincerely,

A handwritten signature in black ink, appearing to read 'SBA', with a long horizontal flourish extending to the right.

Stephen B. Ackerman,
Reg. No. 37761

INFORMATION DISCLOSURE CITATION
IN AN APPLICATION

TSMC-02-1259

10/671,293

Applicant

Chung-Hui Chen

Filing Date

09/25/03

Group Art Unit

(Use several sheets if necessary)

U. S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	PLUNG DATE IF APPROPRIATE
	55064574	9/96	Krauter et al.	307	129	4/7/95
	6307250	10/23/01	Krauter et al.	257	532	4/1/96
	5789964	8/4/98	Voldman	327	380	2/14/97

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
					YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Portion of Pages, Etc.)

	U.S. Patent App. Publication US 2002/0081832 A1 to
	Bernstein et al., Pub. Date 6/27/02, "Intra-level
	Decoupling Capacitor, Method of Manufacture and
	Testing Circuit of the Same".

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.